

Notice of References Cited	Application/Control No. 10/692,666		Applicant(s)/Patent Under Reexamination SHEN ET AL.	
	Examiner Mia M. Thomas		Art Unit 2624	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-4,792,979	12-1988	Nomura et al.	382/169
*	C	US-5,689,575	11-1997	Sako et al.	382/118
*	D	US-7,016,078	03-2006	Shoji, Madoka	358/1.9
*	E	US-7,564,601	07-2009	Angal et al.	358/504
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*	G	US-2005/0185837	08-2005	Takano et al.	382/162
*	H	US-2005/0041261	02-2005	Narushima et al.	358/001.9
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Chan et al. "An Improved Super Resolution with Manifold Learning and Histogram Matching" Spring Verlag Heidelberg 2005, pages 756-762			
	V	NPL Google Search---see attached			
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	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.